

Notice of References Cited	Application/Control No. 09/867,644	Applicant(s)/Patent Under Reexamination JUANG ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,788,523	11-1988	Robbins, William L.	338/309
	C	US-4,418,474	12-1983	Barnett, William P.	29/612
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	O	JP 2000-173801	06-2000	Japan	Sone et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Thomas et al. "Ti-Cu-Ni-Au (TCNA) compatibility with resistor and bilevel crossover circuit processing" (J. Vac. Sci. Technol., Vol. 13, No. 1, Jan/Feb. 1976).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.